

W1.1 Image Quality of Printers

INCITS W1.1 2004-011

Gloss and Gloss Uniformity

Yee Ng, June 29, 2004

Gloss/Gloss Uniformity Ad Hoc Teleconference Meeting Notes:

(6/8/2004 teleconferences)

Present: Yee Ng (Chair, NexPress), Luke Cui (Lexmark), Eric Zeise (Nexpress).

Absent members:

Mike Pointer (National Physical Lab, UK), Pashant Mehta (ImageExpert), John Kessler (Paxar), Sanjay Monie (W.R. Grace), Eric Maggard (HP), Michael Viola (Cabot Corp), Dale Mashtare (Xerox), Peter Morris (HP), Chunghui Kuo (Nexpress)

Next Teleconference: Tuesday, July 6, 2004 @ 1:30 EST.

Agenda:

- (1) Review of the SC28 Plenary meeting relating to Gloss and other IQ issues.
- (2) RIT's microgloss measurement equipment
- (3) Status of the gloss artifact round-robin experiment and the gloss/haze experiment.
- (4) EI2005 discussion
- (5) ISO 19799 WD-CD.

The gloss uniformity ad hoc team met on 6/8/2004 and approved the agenda. YN talked about the Gloss and IQ issues discussed in SC28 Plenary in Nurnberg, Germany. We have recruited a few more of interested parties (from other countries) who are willing to participate in the Standard Development for ISO 19799. We intend to update the 19799 WD with the comments into a version that is ready for CD by the end of July, 2004. As for ISO 19751 (a WD - part 1 from EZ was circulated to the rest of the team), there is a consolidation of differences with ISO/IEC 13660 color extension effort. ISO 19751 (of which Gloss Uniformity is one of its parts – part 2) will concentrate on the appearance-based Standardization. Some of the subjective evaluation work that we have done for gloss uniformity attributes (such as JND work) will need to correlate with common Qa test suite (from TC42, once that becomes available).

YN reported on his visit to RIT to see Professor Arney's new micro-gloss measurement equipment. It is a 2-D measurement instrument that capture all the light that is reflected off the surface. Currently the system is functional, but it requires more real-world samples and the ongoing work is concentrating on the interpretation of the data. YN has asked Dale Mashtare to supply Professor Arney with test charts that have different width gloss streaks to test the capability of the instrument (especially in relationship to paper grain direction effect in measurement). LC reported that he has completed his round of the subjective evaluation of the gloss/haze samples and will be passing the samples to the next group (EM). CK will need to contact LC to discuss the issue of data analysis. The

team agreed to submit an abstract to EI2005 as a place holder. It is assumed that we will have some result on the two subjective round-robin experiments by that time.

Next call-in conference: Tuesday, July 6, 2004, 1:30PM EST.

Proposed agenda:

- (1) Status of the gloss artifact round-robin experiment and the gloss/haze experiment.
- (2) Review and discuss ISO 19799 WD modifications.

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